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Y //	A1	6,534,395	03/18/03	Werkhoven, et al.	43	62 7	03/01	
ay	A2	6,482,740	11/19/02	Soininen, et al.	4:	6	05/ 01	
	А3	6,482,733	11/19/02	Raaijmakers, et al.	4	6	04/2 01	
4.8-4-7/04	A4	6,482,262	11/19/02	Elers, et al.	1	8	10/	
-	A5	6,475,910	11/05/02	Sneh	4	6	09/200	
	A6	6,475,276	11/05/02	Elers, et al.	1	8	10/	
	A7	6,468,924	10/22/02	Lee, et al.	4		05/001	
	A 8	6,451,695	09/17/02	Sneh	4		12/ 00	
1	A9	6,447,933	09/10/02	Wang, et al.	4	5	04/ 01	
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0.00	A11	6,420,189	07/16/02	Lopatin	43		04/ 01	
	A12	6,399,491	06/04/02	Jeon, et al.	43	þ	04/ 01	
4	A13	6,391,785	05/21/02	Satta, et al.	438	4	00/	
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	B2	02/067319	08/29/02	WO	H 1L	21 68	<u> </u>	
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	A4	6,358,829	03/19/02	Yoon, et al.	4 3	59	09/109				
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1	A12	2002/0106846	08/08/02	Seutter, et al.		В	20	02/ 01	
	A13	2002/0105088	08/08/02	Yang, et al.		7	77	10/ 01	
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	A43	5,270,247	12/14/9	3 Sakuma et al.	43		7/8 2
940 M 400 M 500 M	A44	5,278,435	1/11/94	Van Hove et al	. 2		6/8/11/2
Variety that it is a little of	A45	5,281,274	1/25/94	Yoder	1		2/4 3
and bounds of the	A46	5,286,296	2/15/94	Sato et al.			1/9 2
	A47	5,290,748	3/1/94	Knuuttila et al.		4	7/ 92
VI politica de la constanta de	A48	5,294,286	3/15/94	Nishizawa et a	l. 5	6	1/ 93
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	A55	5,336,324	8/9/94	Stall et al.	1	7	12/4 1
	A56	5,338,389	8/16/94	Nishizawa et a	ıl. 1	8	4/2 3
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	A60	5,438,952	8/8/95	Otsuka	1	8	1/3 94
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	A78)5, 6 09,689	3/11/97	Kato et al.	11	719	6/3
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